FERMI-EDGE SINGULARITY IN SINGLE ELECTRON GENERATION

Takeo Kato

- Institute for Solid State Physics
- The University of Tokyo
- Collaboration
- Eiki Iyoda, Tohoku University (From Oct. 2013, The University of Tokyo)

INTRODUCTION



Motivation and purpose

Theory on quality of injected electrons

Moskalets et al. '08, Keeling et al. '08, Fève et al. '08, Degiovanni et al. '09, Mahe et al, '10, Albert et al. '10, Grenier et al. '11, Haack et al. '11, Parmentier et al. '12, Jonckheere et al '12., ...

- Possible mechanism of imperfect anti-bunching
 - Small deviation of experimental parameters
 - Coulomb interaction (edge state, colliding electrons)
 - Fluctuation of environment (background charge, voltage gate etc.)
- Coulomb interaction effect at single-electron generator
- "Electronic" quantum-optical experiment.
 - Characteristic feature of electrons = "Coulomb interaction"

Model Hamiltonian

$$H = H_0 + V$$

$$H_0 = \varepsilon_d d^{\dagger} d + \int \frac{dkka_k^{\dagger}a_k}{dkka_k^{\dagger}a_k} + Ud^{\dagger} d\tilde{a}_0^{\dagger} \tilde{a}_0$$
quantum dot Chiral edge Coulomb interaction
$$V = \underbrace{g(\tilde{a}_0^{\dagger}d + d^{\dagger}\tilde{a}_0)}_{\text{tunneling amplitude}} \qquad \tilde{a}_0 \equiv \tilde{a}_{r=0}$$

$$\tilde{a}_r = \frac{1}{\sqrt{2\pi}} \int dke^{ikr}a_k$$
Real-space representation
$$\underbrace{U(g \text{ chiral edge channel}}_{0} \tilde{a}_r$$

$$\underbrace{U(g \text{ chiral edge channel}}_{0} \tilde{a}_r$$

$$\underbrace{W = \frac{1}{\sqrt{2\pi}} \int dke^{ikr}a_k}_{0} \tilde{a}_r$$

$$\underbrace{W = \frac{1}{\sqrt{2\pi}} \int dke^{ikr}a_k}_{0} \tilde{a}_r$$

$$\underbrace{W = \frac{1}{\sqrt{2\pi}} \int dke^{ikr}a_k}_{0}$$



METHOD



(1) survival probability

$$P(t) = \langle d^{\dagger}(t)d(t) \rangle$$

(2) density matrix of emitted electrons

$$o(r, r', t) = \langle a_{r'}^{\dagger}(t) a_r(t) \rangle$$

Information of an emitted electron (including its coherence)

Diagrammatic Expansion (1)

$$\begin{split} H &= H_0 + V \\ H_0 &= \varepsilon_d d^{\dagger} d + \int dk k a_k^{\dagger} a_k + U d^{\dagger} d\tilde{a}_0^{\dagger} \tilde{a}_0 \\ V &= g(\tilde{a}_0^{\dagger} d + d^{\dagger} \tilde{a}_0) \longleftarrow \text{perturbation} \\ \end{split}$$

$$\begin{split} \text{Formal expansion in V} \\ \langle \hat{O}(t) \rangle &= \sum_{m=0}^{\infty} \sum_{n=0}^{\infty} (-i)^m i^n \int_{0 \le t_1 \le \cdots \le t_m \le t} dt_1' \cdots dt_n' \\ &\leq \langle \psi(0) | V_I(t_1') \cdots V_I(t_n') O_I(t) V_I(t_m) \cdots V_I(t_1) | \psi(0) \rangle \end{split}$$

interaction representation

$$V_I(t) = e^{iH_0t} V e^{-iH_0t}$$
$$O_I(t) = e^{iH_0t} O e^{-iH_0t}$$

Diagrammatic Expansion (2)

$$V=g(ilde{a}_0^\dagger d+d^\dagger ilde{a}_0)$$
 : vertex

Each term in expansion series

$$-i)^2 \int_{0 \le t_1 \le t_2 \le t} dt_1 dt_2 \langle O_I(t) V_I(t_2) V_I(t_1) \rangle \square$$



 $i^2 \int_{0 \le t_1' \le t_2' \le t} dt_1' dt_2' \langle V_I(t_1') V_I(t_2') O_I(t) \rangle \quad \blacksquare \qquad \blacksquare$

$$(-i)i \int_{0 \le t_1, t_1' \le t} dt_1 dt_1' \langle V_I(t_1') O_I(t) V_I(t_1) \rangle$$



Diagrammatic Expansion (3)

Survival probability

Schoeller-Schön 1994 U. Weiss "Dissipative Quantum Systems"



Lowest-order approximation

Self-energy



exponential decay

Effect of Coulomb interaction



 δ : phase shift

Analytic calculation of G(t)

- Singular integral approach (Nozières-de Dominicis 1969)
- Bosonization method (Schotte-Schotte 1969)
- Determinant formula + Riemann-Hilbert factorization (Abanin-Levitov 2004, 2005)





RESULT







Purity and coincidence probability





coincidence probability

$$\begin{split} P_{12} &= \int dk \int dk' \langle (b_k^{(1)})^{\dagger} b_k^{(1)} (b_{k'}^{(2)})^{\dagger} b_{k'}^{(2)} \rangle = \frac{1+\mathcal{P}}{2} \\ \end{split} \\ \begin{aligned} \mathsf{Purity} \quad \mathcal{P} &= \frac{\mathrm{Tr}(\rho^2)}{(\mathrm{Tr}\rho)^2} = \int dk \int dk' \rho(k,k') \rho(k',k) \\ \mathcal{P} &\to 1 \quad P_{12} = 1 \ \text{: complete anti-bunching (Fermion)} \\ \mathcal{P} &\to 0 \quad P_{12} = 1/2 \ \text{: classical} \end{split}$$





Suppression of small-energy excitation

Pure dephasing strongly affect quality of emitted electrons.

Summary

- Fermi-edge singularity induces singular behavior on single electron generation.
 - Survival probability
 - density matrix (including coherence of injected electrons)
- Energy spectrum of injected electrons (δ : phase shift)
 - exponent $-2\delta/\pi$... small-energy electron excitation
 - exponent $(\delta/\pi)^2$... decay of the main peak
- Purity (= degree of anti-bunching)
 - (modest) suppression due to Coulomb interaction
- Other effect
 - finite-temperature, pure dephasing effect
- Direct observation of many body effect through coherence of emitted electrons.